



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005  
& ANSI/NCSL Z540-1-1994

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**CALIBRATION**

Valid to: July 18, 2012

Certificate Number: AC-1286

**I. Electromagnetic - DC/Low Frequency**

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
DC Voltage - Source	Up to 100 mV 100 mV to 1 V	3 μV/V 2 μV/V	Fluke 732A and 752A	Local Procedure or GIDEP/OEM Sourced Procedures
	(1 to 10) V (10 to 100) V 100 V to 1 kV	1.2 μV/V 2 μV/V 2 μV/V	Wavetek 7004N Fluke 732A and 752A	
	(10 to 100) V 100 V to 1 kV	4.8 μV/V + 5 μV 5.1 μV/V + 50 μV	Fluke 752A and HP 3458A Opt 002	
DC Voltage - Source <sup>3,9</sup>	Up to 330 mV 330 mV to 3.3 V (3.3 to 33) V (33 to 330) V 100 V to 1.02 kV	20 μV/V + 1 μV 11 μV/V + 2 μV 12 μV/V + 20 μV 18 μV/V + 150 μV 18 μV/V + 1.5 mV	Fluke 5520A	
DC Voltage - Measure <sup>3,9</sup>	Up to 100 mV 100 mV to 1 V (1 to 10) V (10 to 100) V 100 V to 1 kV	5.5 μV/V + 300 nV 5.1 μV/V + 300 nV 4.6 μV/V + 500 nV 6.5 μV/V + 30 μV 18.5 μV/V + 100 μV	HP 3458A Opt 002	
DC Current - Measure	(10 to 100) μA 100 μA to 1 mA (1 to 10) mA (10 to 100) mA 1 mA to 1 A (1 to 10) A (10 to 20) A	10 μA/A + 30 pA 10 μA/A + 300 pA 10 μA/A + 3 nA 10 μA/A + 30 nA 10 μA/A + 300 nA 10 μA/A + 3 μA 120 μA/A + 30 μA	Standard Resistors with HP 3458A Opt 002  Fluke Y5020 with HP 3458A Opt 002	



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DC Current - Source <sup>3,9</sup>	Up to 320 µA 320 µA to 3.2 mA (3.2 to 32) mA (32 to 320) mA 320 mA to 1.1 A (1.1 to 2.9) A (2.9 to 11) A (11 to 20.5) A	150 µA/A + 20 nA 100 µA/A + 50 nA 100 µA/A + 250 nA 100 µA/A + 2.5 µA 200 µA/A + 40 µA 380 µA/A + 40 µA 500 µA/A + 500 µA 1 mA/A + 750 µA	Fluke 5520A	Local Procedure or GIDEP/OEM Sourced Procedures
DC Current - Measure <sup>3,9</sup>	(0 to 100) µA 100 µA to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A	17 µA/A + 800 pA 17 µA/A + 5 nA 17 µA/A + 50 nA 32 µA/A + 500 nA 100 µA/A + 10 µA	HP 3458A Opt 002	
DC Power <sup>3,9</sup> - (33 to 1 020) V output	330 µA to 3 A (3 to 20.5) A	0.02 % 0.07 %	Fluke 5520A	
Electrical Simulation of Thermocouples <sup>3,9</sup>				
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1 000) °C	0.5 °C 0.17 °C 0.15 °C 0.17 °C 0.22 °C	Fluke 5520A	
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1 200) °C	0.28 °C 0.17 °C 0.15 °C 0.18 °C 0.24 °C		
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1 000) °C (1 000 to 1 372) °C	0.34 °C 0.19 °C 0.17 °C 0.27 °C 0.4 °C		
Type R	(0 to 250) °C (250 to 400) °C (400 to 1 000) °C (1 000 to 1 767) °C	0.57 °C 0.36 °C 0.34 °C 0.4 °C		

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Electrical Simulation of Thermocouples <sup>3,9</sup> (cont.) Type S  Type T	0 to 250) °C (250 to 1 000) °C (1 000 to 1 400) °C (1 400 to 1 767) °C  (-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.47 °C 0.36 °C 0.37 °C 0.46 °C  0.63 °C 0.25 °C 0.17 °C 0.15 °C	Fluke 5520A	Local Procedure or GIDEP/OEM Sourced Procedures
AC Voltage - Measure 22 mV Range	<b>2 mV</b> (10 to 20) Hz 20 Hz to 50 kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz <b>10 mV</b> (10 to 20) Hz 20 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz <b>20 mV</b> (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz	2.7 mV/V 2.2 mV/V 2.5 mV/V 2.9 mV/V 4.8 mV/V 5.2 mV/V  322 µV/V 282 µV/V 302 µV/V 501 µV/V 701 µV/V 1.2 mV/V 1.5 mV/V  281 µV/V 181 µV/V 141 µV/V 201 µV/V 450 µV/V 650 µV/V 1.1 mV/V 1.3 mV/V	Fluke 792A with Agilent 3458A Opt 002 & Fluke 5700A	





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AC Voltage - Measure (cont.) 70 V Range       220 V Range       1 kV Range	<b>60 V</b> (10 to 20) Hz (20 to 40) Hz (40 to 100) Hz 100 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz  <b>100 V</b> (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz  <b>200 V</b> (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz  <b>1 kV</b> 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz	190 µV/V 60 µV/V 26 µV/V 21 µV/V 50 µV/V 65 µV/V 130 µV/V  190 µV/V 65 µV/V 31 µV/V 65 µV/V 70 µV/V  191 µV/V 63 µV/V 33 µV/V 63 µV/V 73 µV/V  33 µV/V 63 µV/V 73 µV/V	Fluke 792A & Agilent 3458A Opt 002 & Fluke 5700A	Local Procedure or GIDEP/OEM Sourced Procedures
AC Voltage - Measure <sup>3,9</sup>	<b>Up to 10 mV</b> 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz  <b>(10 to 100) mV</b> 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz  <b>100 mV to 1 V</b> 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz  <b>(1 to 10) V</b> 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz	200 µV /V + 1.1 µV 300 µV /V + 1.1 µV 1 mV/V + 1.1 µV  70 µV/V + 2 µV 140 µV/V + 2 µV 300 µV/V + 2 µV  70 µV/V + 20 µV 140 µV/V + 20 µV 300 µV/V + 20 µV  70 µV/V + 200 µV 140 µV/V + 200 µV 300 µV/V + 200 µV	HP 3458A Opt 002	





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AC Current - Source <sup>3,9</sup>	<p><b>(33 to 330) µA</b>  (10 to 20) Hz  (20 to 45) Hz  45 Hz to 1 kHz  (1 to 5) kHz  (5 to 10) kHz  (10 to 30) kHz</p> <p><b>330 µA to 3.3 mA</b>  (10 to 20) Hz  (20 to 45) Hz  45 Hz to 1 kHz  (1 to 5) kHz  (5 to 10) kHz  (10 to 30) kHz</p> <p><b>(3.3 to 33) mA</b>  (10 to 20) Hz  (20 to 45) Hz  45 Hz to 1 kHz  (1 to 5) kHz  (5 to 10) kHz  (10 to 30) kHz</p> <p><b>(33 to 330) mA</b>  (10 to 20) Hz  (20 to 45) Hz  45 Hz to 1 kHz  (1 to 5) kHz  (5 to 10) kHz  (10 to 30) kHz</p> <p><b>330 mA to 1.1 A</b>  (10 to 45) Hz  45 Hz to 1 kHz  (1 to 5) kHz  (5 to 10) kHz</p> <p><b>(1.1 to 3) A</b>  (10 to 45) Hz  45 Hz to 1kHz  (1 to 5) kHz  (5 to 10) kHz</p> <p><b>(3 to 11) A</b>  (45 to 100) Hz  100 Hz to 1kHz  (1 to 5) kHz</p>	<p>2 mA/A + 100 nA  1.5 mA/A + 100 nA  1.3 mA/A + 100 nA  3 mA/A + 150 nA  8 mA/A + 200 nA  16 mA/A + 400 nA</p> <p>2 mA/A + 150 nA  1.3 mA/A + 100 nA  1 mA/A + 150 nA  2 mA/A + 200 nA  5 mA/A + 300 nA  10 mA/A + 600 nA</p> <p>1.8 mA/A + 2 µA  900 µA/A + 2 µA  400 µA/A + 2 µA  800 µA/A + 2 µA  2 mA/A + 3 µA  4 mA/A + 4 µA</p> <p>1.8 mA/A + 20 µA  900 µA/A + 20 µA  400 µA/A + 20 µA  1 mA/A + 50 µA  2 mA/A + 100 µA  4 mA/A + 200 µA</p> <p>1.8 mA/A + 100 µA  500 µA/A + 100 µA  6 mA/A + 1 mA  25 mA/A + 5 mA</p> <p>1.8 mA/A + 100 µA  600 µA/A + 100 µA  6 mA/A + 1 mA  25 mA/A + 5 mA</p> <p>600 µA/A + 2 mA  1 mA/A + 2 mA  30 mA/A + 2 mA</p>	Fluke 5520A	Local Procedure or GIDEP/OEM Sourced Procedures





PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Resistance - Source <sup>3,9</sup>	Up to 11 Ω (11 to 33) Ω (33 to 110) Ω 110 Ω to 1.1 kΩ (1.1 to 11) kΩ (11 to 110) kΩ 110 kΩ to 1.1 MΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ (11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ 330 MHz to 1.1 GΩ	40 μΩ/Ω + 1 mΩ 30 μΩ/Ω + 1.5 mΩ 28 μΩ/Ω + 1.4 mΩ 28 μΩ/Ω + 2 mΩ 28 μΩ/Ω + 20 mΩ 28 μΩ/Ω + 200 mΩ 32 μΩ/Ω + 2 Ω 60 μΩ/Ω + 30 Ω 130 μΩ/Ω + 50 Ω 250 μΩ/Ω + 2.5 kΩ 500 μΩ/Ω + 3 kΩ 3 mΩ/Ω + 100 kΩ 15 mΩ/Ω + 500 kΩ	Fluke 5520A	Local Procedure or GIDEP/OEM Sourced Procedures
Resistance - Measure <sup>3,9</sup>	10 Ω 100 Ω 1 kΩ 10 kΩ 100 kΩ 1 MΩ 10 MΩ 100 MΩ 300 MΩ	16 μΩ/Ω + 50 μΩ 11 μΩ/Ω + 500 μΩ 9 μΩ/Ω + 500 μΩ 9 μΩ/Ω + 5 mΩ 9 μΩ/Ω + 500 mΩ 13 μΩ/Ω + 2 Ω 51 μΩ/Ω + 100 Ω 500 μΩ/Ω + 1 kΩ 5 mΩ/Ω + 10 kΩ	HP 3458A Opt 002	
Resistance - Measure <sup>3,9</sup>	400 MΩ 640 MΩ 1.09 GΩ	2.2 mΩ/Ω 3.5 mΩ/Ω 5.9 mΩ/Ω	HP 3458A Opt 002 & Standard Resistor	
Resistance - Measure	100 mΩ 1 Ω 10 Ω 100 Ω 1 kΩ 10 kΩ 100 kΩ 1 MΩ 10 MΩ 100 MΩ	220 nΩ 1 μΩ 10 μΩ 100 μΩ 1.5 mΩ 15 mΩ 400 mΩ 4.6 Ω 160 Ω 2.4 kΩ	Guildline 9975 Resistance Bridge and Standard Oil Bath Resistors	
Resistance - Source	1 mΩ 1 Ω 10 Ω 100 Ω 1 kΩ 10 kΩ 100 kΩ 1 MΩ 10 MΩ 100 MΩ	220 nΩ 1 μΩ 10 μΩ 100 μΩ 1.5 mΩ 15 mΩ 400 mΩ 4.6 Ω 160 kΩ 2.4 kΩ	Guildline 9975 Resistance Bridge and Standard Oil Bath Resistors	



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Capacitance - Measure 100 pF to 200 µF 200 µF to 110 mF	50 Hz to 5 kHz DC	0.02 % 0.1 %	GR 1689 Fluke 5700A & HP 3458A	Local Procedure or GIDEP/OEM Sourced Procedures
Phase - Measure (10 to 100) mV 100 mV to 120 V	10 Hz to 10 kHz (10 to 50) kHz (50 to 100) kHz 10 Hz to 50 kHz (50 to 100) kHz	0.21 ° 0.36 ° 0.72 ° 0.05 ° 0.36 °	KH 6620	
Rise Time – Measure	=>17.5 ps	3 %	TEK TDS 8200 w/ 80E04	
Sine Wave Flatness 100 mV to 5.5 V	50 kHz to 1.1 GHz	1.2 %	HP 436A & HP 8482A	
Leveled Sine Wave Harmonic Amplitude	100 kHz to 3 GHz	1.8 dB	HP 8563E	
<b>Oscilloscopes</b> <sup>3,9</sup> Amplitude - DC 50 Ω 1 MΩ Amplitude - Square Wave 50 Ω 1 MΩ Leveled Sine Wave (ref 50 kHz) [5 mV to 5.5 V] p-p Time Marker Rise Time	(-6.6 to 6.6) V (-130 to 130) V ±1 mV to ±6.6 V p-p 10 Hz to 10 kHz ±1 mV to ±130 V p-p 10 Hz to 1 kHz (1 to 10) kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 600 MHz to 1.1 GHz 5 s to 50 ms 20 ms to 2 ns =>300 ps	2.5 mV/V + 40 µV 500 µV/V + 40 µV 2.5 mV/V + 40 µV 1 mV/V + 40 µV 2.5 mV/V + 40 µV 35 µV/V + 300 µV 40 µV/V + 300 µV 60 µV/V + 300 µV 70 µV/V + 300 µV (25 + 1 000t) µs/s 2.5 µs/s +0 ps/ -100 ps	Fluke 5520A/ SC1100	

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Capacitance - Source <sup>3</sup> 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz (10 to 600) Hz (10 to 300) Hz (10 to 150) Hz (10 to 120) Hz (10 to 80) Hz (0 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	190 pF to 1.1 nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 110) nF (110 to 330) nF 330 nF to 1.1 µF (1.1 to 3.3) µF (3.3 to 11) µF (11 to 33) µF (33 to 110) µF (110 to 330) µF 330 µF to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	5 mF/F + 10 pF 5 mF/F + 10 pF 2.6 mF/F + 10 pF 2.6 mF/F + 100 pF 2.5 mF/F + 300 pF 2.6 mF/F + 1 nF 2.5 mF/F + 3 nF 2.6 mF/F + 10 nF 4 mF/F + 30 nF 4.5 mF/F + 100 nF 4.5 mF/F + 300 nF 4.5 mF/F + 1 µF 4.5 mF/F + 3 µF 4.5 mF/F + 10 µF 7.5 mF/F + 30 µF 11 mF/F + 100 µF	Fluke 5520A w/ SC1100	Local Procedure or GIDEP/OEM Sourced Procedures

## II. Time & Frequency

PARAMETER/ EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Frequency - Source	10 MHz DC to 20 MHz	5.2 parts in 10 <sup>12</sup> 5.2 parts in 10 <sup>12</sup>	Datum 9390 GPS Receiver	Local Procedure or GIDEP/OEM Sourced Procedures
Frequency - Source <sup>3</sup>	0.01 Hz to 2 MHz	2.6 µHz/Hz + 5 µHz	Fluke 5520A	Local Procedure or GIDEP/OEM Sourced Procedures

## III. Thermodynamic

PARAMETER/ EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Temperature - Source	(-190 to 420) °C (420 to 550) °C (550 to 950) °C	0.011 °C 0.25 °C 0.37 °C	Hart 1590 w/ SPRT Hart 1590 w/5624 SPRT Hart 1590 w/5624 SPRT	Local Procedure or GIDEP/OEM Sourced Procedures

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Temperature - Measure <sup>3</sup>	(-195 to 0) °C (0 to 200) °C (200 to 420) °C	0.02 °C 0.03 °C 0.04 °C	Azonix A1011 w/ Probe	Local Procedure or GIDEP/OEM Sourced Procedures
Relative Humidity	(10 to 95) %RH	1.2 % of reading	General Eastern Hygro M2 chilled mirror in controlled chamber	
Relative Humidity	(5 to 99) %RH	0.38 % of reading	Thunder Scientific 9000	

#### IV. Mechanical

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Mass <sup>9</sup>	(1 to 500) mg (1,2,3,5) g (10, 20) g 30 g 50 g 100 g (200, 300, 500, 1 000) g 2 kg 3 kg 5 kg 10 kg 20 kg 30 kg	2 µg 7 µg 11 µg 30 µg 40 µg 55 µg 120 µg 870 µg 4.2 mg 4.6 mg 6.5 mg 11.9 mg 17 mg	UMX5 UMX5 AX106 AX106 AX106 AX106 AT1005 PR2004 KA10-3/P KA10-3/P KA10-3/P KA30-3/P KA30-3/P	Local Procedure or GIDEP/OEM Sourced Procedures
Mass Comparators	Up to 5 g (5 to 100) g (100 to 2 100) g (1 to 15) kg (15 to 30) kg	2 µg 2 µg 103 µg 9.3 mg 17 mg	Master Weight Set	
Torque Arms	2.5 in 5 in 10 in 40 in	0.0005 in 0.0005 in 0.0005 in 0.0020 in	Grade 2 Gage Blocks, Surface Plate and Height Gage	



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Pressure - Nitrogen  Effective Area of Piston/Cylinder Dead Weight Testers  Pressure Standards	(2 to 1 000) psi  (0.2 to 1 000) psi	20 parts in 10 <sup>6</sup>  20 parts in 10 <sup>6</sup>	Ruska 2465 with Autoprompt	Local Procedure or GIDEP/OEM Sourced Procedures
Pressure Gages <sup>9</sup>	Up to 1 000 psi	0.01 %	Mensor PCS 400 with Transducers	
	Up to 4 000 psi	0.1 %	Heise 710A	
	Up to 12 000 psi	0.01 %	Ruska 2481	
	Up to 15 psia (15 to 55) psia Up to 40 psi	0.001 psi 0.002 psi 0.002 psi	King Nutronics 3682 Air Data Calibrator	
Pressure - Hydraulic	(8 to 4 000) psi (4 000 to 15 000) psi	50 parts in 10 <sup>6</sup> 60 parts in 10 <sup>6</sup>	Ruska 2481 Dead Weight Tester	
Pressure - Hydraulic <sup>3</sup>	Up to 1 000 psi (1 000 to 5 000) psi	0.025 % 0.05 %	Documenting Process Calibrator with 700 Series Transducers	
	(8 to 4 000) psi (4 000 to 15 000) psi	50 parts in 10 <sup>6</sup> 60 parts in 10 <sup>6</sup>	Ruska 2481 Dead Weight Tester	
	Up to 50 psi (50 to 3 000) psi	0.02 psi 0.1 %	Druck DPI 310A	

**V. Dimensional**

<b>PARAMETER / EQUIPMENT</b>	<b>RANGE</b>	<b>CALIBRATION &amp; MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]</b>	<b>REFERENCE STANDARD OR EQUIPMENT</b>	<b>METHOD(S)</b>
Gage Blocks	Up to 1 in (1 to 2) in (2 to 3) in (3 to 4) in (4 to 5) in (5 to 6) in (6 to 7) in (7 to 8) in (8 to 10) in (10 to 12) in (12 to 16) in (16 to 20) in	2.8 µin 3.2 µin 3.6 µin 4 µin 10.1 µin 10.9 µin 11.8 µin 12.7 µin 14.6 µin 16.5 µin 20.6 µin 24.9 µin	Gage Blocks Grade 0.5 ≤ 4 in (100 mm) 1 Grade (5 to 20) in (500 mm) with Edmunds Gage Block Comparator	Local Procedure or GIDEP/OEM Sourced Procedures
Surface Plate Flatness	(8 X 12 to 72 X 72) in	17 µin	Electronic Levels	
Linear Measuring Machines <sup>5</sup>	Up to 2 in (2 to 8) in	8.8 µin (6.5 + 3.9L) µin	Grade 2 Gage Blocks	
Micrometers <sup>3,5,9</sup>	Up to 12 in (12 to 40) in	(30 + 3.1L) µin (63 + 4.4L) µin	Grade 2 Gage Blocks and Surface Plate	
Calipers <sup>3,5,9</sup>	Up to 12 in (12 to 40) in	(60 + 2.2 L) µin (75 + 4.2L) µin	Grade 2 Gage Blocks and Surface Plate	
Dial Indicators <sup>3,9</sup> Digital Indicators <sup>3,9</sup>	Up to 6 in	48.6 µin	Pratt & Whitney Model C Supermicrometer	
Height Gages <sup>3,5,9</sup>	Up to 24 in	(78 + 2.6L) µin	Grade 2 Gage Blocks and Surface Plate	
Dial Indicator Calibrators <sup>5</sup>	Up to 1 in	10.5 µin	Grade 2 Gage Blocks	
Plain Plug & Pin Gages <sup>3,5</sup>	Up to 8 in	(30 + 2.9L) µin	Universal Measuring Machine and Grade 2 Gage Blocks	
Length Standards - End Rods <sup>5</sup>	(1 to 39) in	(30 + 3.7L) µin		



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Threaded Set - Working Plug Gages Pitch Diameter <sup>5</sup>	Up to 2 in (2 to 8) in	65 µin (65 + 2L) µin	Pratt & Whitney Model C Supermicrometer and Grade 2 Gage Blocks	Local Procedure or GIDEP/OEM Sourced Procedures

- Notes:**
1. Calibration and Measurement Capabilities (CMC) (Expanded Uncertainties) are based on approximately a 95% confidence interval, using a coverage of  $k=2$ .
  2. This laboratory offers calibration services in its laboratory and on-site at customer-designated locations. Since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
  3. These parameters are available for on-site calibration.
  4. CMC for Electromagnetic-DC/Low Frequency may not include possible contributions from a "best available" unit under test.
  5. The use of (L) signifies Length in inches.
  6. The use of (R) signifies Resolution of the unit under test.
  7. The use of (t) indicates Time in seconds.
  8. The laboratory maintains a satellite location where no activities other than calibrations are performed. The address of this site is Tektronix Service Solutions, 400 Britannia Road East, Unit 2, Mississauga, Ontario, Canada L4Z 1X9. POC: Vince Casali. Telephone: 905-241-3021.
  9. These parameters are also available at the Mississauga, Ontario satellite site.
  10. This scope is part of and must be included with the Certificate of Accreditation No. AC-1286.




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Vice President